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| Notice of References Cited | Application/Control No. 10/722,290 | Applicant(s)/Patent Under Reexamination HAHN ET AL. | |
| | Examiner Robert T. Crow | Art Unit 1634 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|---------------------|----------------|
| * | A | US-2003/0123322 | 07-2003 | Chung et al. | 366/165.1 |
| * | B | US-4,750,556 | 06-1988 | del Valle P. et al. | 165/169 |
| * | C | US-2002/0047003 | 04-2002 | Bedingham et al. | 219/388 |
| | D | US- | | | |
| | E | US- | | | |
| | F | US- | | | |
| | G | US- | | | |
| | H | US- | | | |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|--------------|----------------|
| | N | WO99/36576 | 07-1999 | US | Taylor et al | 12Q 1/68 |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | Aldrich Techware Catalog (Sigma-Aldrich, St. Louis, MO page 181 (1995-1996). |
| | V | |
| | W | |
| | X | |

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.